

2016

1. T. Satoh, H. Niimi, N. Kikuchi, M. Fujii, T. Seki, J. Matsuo,
"Solvent-free silver-nanoparticle surface-assisted laser desorption/ionization imaging mass spectrometry of the Irganox 1010 coated on polystyrene",
International Journal of Mass Spectrometry, 404, 1-7, (2016.6).
2. M. Fujii, R. Shishido, T. Satoh, S. Suzuki, J. Matsuo
"Effects of Molecular Weight and Cationization Agent on the Sensitivity of Bi Cluster SIMS",
Rapid Commun. Mass Spectrom., 30, 1722-1726, (2016.7).
3. Toshio Seki, Yu Yoshino, Takehiko Senoo, Kunihiro Koike, Takaaki Aoki and Jiro Matsuo.
"Reactive etching by ClF₃-Ar neutral cluster beam with scanning"
Japanese Journal of Applied Physics, Volume 55, Number 6S2(2016)
4. Takaaki Aoki, Toshio Seki, Jiro Matsuo
"Molecular dynamics simulations study of nano particle migration by cluster impact"
Surface and Coatings Technology.(doi:10.1016/j.surfcoat.2016.04.053)(2016)
5. Kanji Suzuki, Masakazu Kusakari, Makiko Fujii, Toshio Seki, Takaaki Aoki and Jiro Matsuo,
"Development of Low-vacuum SIMS instruments with large cluster Ion beam"
Surface and Interface Analysis, Vol.48, No.11 (2016, Sep) 1119-1121
6. 佐藤貴弥, 藤井麻樹子, 松尾二郎
"レーザー離脱イオン化イメージング質量分析法による表面分析の可能性"
Journal of Surface Analysis, 23 巻(2016), 1 号
(doi:10.1384/jsa.23.2)
7. 松尾二郎, 藤井麻樹子, 瀬木利夫, 青木学聡
"クラスタービーム技術の新展開"
精密工学会誌, 82 巻(2016), 4 号, P.309-314
(doi:10.2493/jjspe.82.309)
8. 松尾二郎, 藤井麻樹子, 瀬木利夫, 青木学聡
"クラスタービーム技術の最近の進展-ナノ加工からバイオ材料評価まで-"
Journal of the Vacuum Society of Japan, 59 巻(2016), 5 号, P.113-120
(doi:10.3131/jvsj.59.113)

2015

1. G. MorienaY. Yokoyama, S. Aoyagi, M. Fujii, J. Matsuo, J. S. Fletcher, N. P. Lockyer, J. C. Vickerman, I. S. Gilmore, R. Havelund, M. P. Seah;
"Peptide fragmentation and structural analysis by means of ToF-SIMS using huge cluster ion sources", Anal. Chem., 88, pp. 3592-3597, (2016.2).
2. Kusakari, M., Fujii, M., Seki, T., Matsuo, J.
"Observation of Liquid water with Ambient SIMS"
Transactions of the Materials research Society of Japan.(2016) (Accept)
3. Kusakari, M., Fujii, M., Seki, T., Aoki, T., Matsuo, J.
"Development of ambient SIMS using mega-electron-volt-energy ion probe"
Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics 34 (3), 03H111 (2016)

4. Seki, T., Kusakari, M., Fujii, M., Aoki, T., Matsuo, J.
"Ambient analysis of liquid materials with Wet-SIMS"
Nuclear Instruments and Methods in Physics Research,
Section B: Beam Interactions with Materials and Atoms 371, pp. 189-193(2016.3)
5. Yamamoto, H., Seki, T., Matsuo, J., Koike, K., Kozawa, T.
"High-aspect-ratio patterning by ClF₃-Ar neutral cluster etching"
Microelectronic Engineering 141, pp. 145-149(2015.6)
6. R. Shishido, M. Fujii, T. Seki, T. Aoki, J. Matsuo and S. Suzuki
"Yields and Images of Secondary Ions from Organic Materials by Different Primary Bi ions
in Time-of-Flight Secondary Ion Mass Spectrometry"
Rapid Commun. Mass Spectrom., Wiley, 30, pp.476-482, (2016.1).
7. H. Gnaser, M. Kusakari, M. Fujii, T. Seki, T. Aoki and J. Matsuo;
"Secondary ion emission from leucine and isoleucine under argon gas-cluster ion bombardment"
Journal of Vacuum Science and Technology B, vol.34, 03H102, (2016.1).
8. M. Kusakari, H. Gnaser, M. Fujii, T. Seki, T. Aoki and J. Matsuo
Molecular cluster emission in sputtering of amino acids by argon gas-cluster ions
International Journal of Mass Spectrometry, 383-384, 31-37, 2015.